Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/757,192	DEWITT ET AL.
Examiner	Art Unit
Raymond Phan	2111

	SEARCHED			
Class	Subclass	Date	Examiner	
710	260-269	11/23/2005	RP	
712	200,244	11/26/2005	RP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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	1			

SEAF (INCLUDING S	RCH NOTES SEARCH STRATE	EGY)
	DATE	
EAST	11/23/20	005 RP